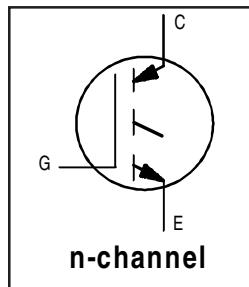


# IRGVH50F

Fast Speed IGBT

## Features

- Electrically Isolated and Hermetically Sealed
- Simple Drive Requirements
- Latch-proof
- Fast Speed operation 3 kHz - 8 kHz
- High operating frequency
- Switching-loss rating includes all "tail" losses



$V_{CES} = 1200V$
$V_{CE(on)} \text{ max} = 2.9V$
@ $V_{GE} = 15V$ , $I_C = 25A$

## Description

Insulated Gate Bipolar Transistors (IGBTs) from International Rectifier have higher usable current densities than comparable bipolar transistors, while at the same time having simpler gate-drive requirements of the familiar power MOSFET. They provide substantial benefits to a host of high-voltage, high-current applications.

The performance of various IGBTs varies greatly with frequency. Note that IR now provides the designer with a speed benchmark ( $f_{IC/2}$ , or the "half-current frequency"), as well as an indication of the current handling capability of the device.



TO-258AA

## Absolute Maximum Ratings

	Parameter	Max.	Units
$V_{CES}$	Collector-to-Emitter Breakdown Voltage	1200	V
$I_C @ T_C = 25^\circ C$	Continuous Collector Current	45	A
$I_C @ T_C = 100^\circ C$	Continuous Collector Current	25	
$I_{CM}$	Pulsed Collector Current ①	180	
$I_{LM}$	Clamped Inductive Load Current ②	90	
$V_{GE}$	Gate-to-Emitter Voltage	$\pm 20$	V
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	200	W
$P_D @ T_C = 100^\circ C$	Maximum Power Dissipation	80	
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 150	$^\circ C$
	Lead Temperature	300 (0.063in./1.6mm from case for 10s)	
	Weight	10.5 (typical)	g

## Thermal Resistance

	Parameter	Min	Typ	Max	Units	Test Conditions
$R_{thJC}$	Junction-to-Case	—	—	0.625	$^\circ C/W$	
$R_{thCS}$	Case-to-Sink	—	0.21	—		
$R_{thJA}$	Junction-to-Ambient	—	—	30		

For footnotes refer to the last page

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### Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

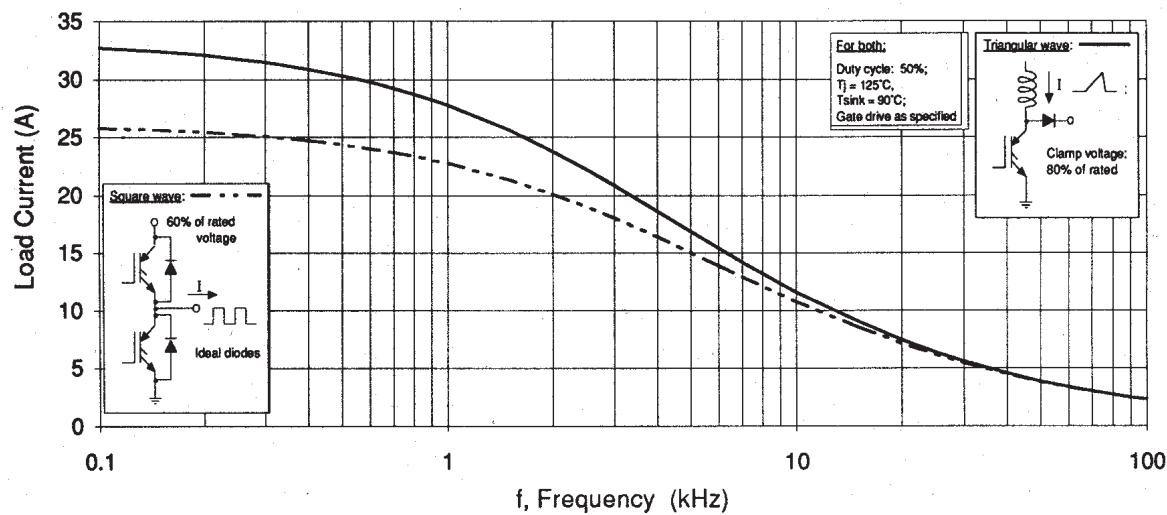
	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{CES}}$	Collector-to-Emitter Breakdown Voltage	1200	—	—	V	$V_{\text{GE}} = 0\text{V}, I_C = 100\ \mu\text{A}$
$V_{(\text{BR})\text{ECS}}$	Emitter-to-Collector Breakdown Voltage ③	22	—	—	V	$V_{\text{GE}} = 0\text{V}, I_C = 1.0\text{ A}$
$V_{\text{CE}(\text{ON})}$	Collector-to-Emitter Saturation Voltage	—	2.1	2.9	V	$I_C = 25\text{A}$ $V_{\text{GE}} = 15\text{V}$
		—	2.5	—		$I_C = 45\text{A}$ See Fig.2, 5
		—	2.4	—		$I_C = 25\text{A}, T_J = 125^\circ\text{C}$
$V_{\text{GE}(\text{th})}$	Gate Threshold Voltage	3.0	—	6.0		$V_{\text{CE}} = V_{\text{GE}}, I_C = 250\ \mu\text{A}$
$\Delta V_{\text{GE}(\text{th})}/\Delta T_J$	Temperature Coeff. of Threshold Voltage	—	-14	—	mV/°C	$V_{\text{CE}} = V_{\text{GE}}, I_C = 250\ \mu\text{A}$
$g_{\text{fe}}$	Forward Transconductance ④	7.5	—	—	S	$V_{\text{CE}} = 100\text{V}, I_C = 25\text{A}$
$I_{\text{CES}}$	Zero Gate Voltage Collector Current	—	—	100	$\mu\text{A}$	$V_{\text{GE}} = 0\text{V}, V_{\text{CE}} = 960\text{V}$
		—	—	1200		$V_{\text{GE}} = 0\text{V}, V_{\text{CE}} = 960\text{V}, T_J = 125^\circ\text{C}$
$I_{\text{GES}}$	Gate-to-Emitter Leakage Current	—	—	$\pm 100$	nA	$V_{\text{GE}} = \pm 20\text{V}$

### Switching Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

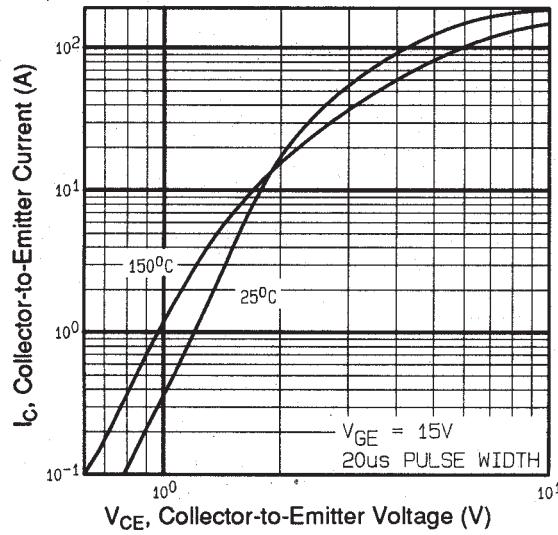
	Parameter	Min.	Typ.	Max.	Units	Conditions
$Q_g$	Total Gate Charge (turn-on)	—	—	100	nC	$I_C = 25\text{A}$
$Q_{ge}$	Gate - Emitter Charge (turn-on)	—	—	21		$V_{\text{CC}} = 400\text{V}$ See Fig. 8 ⑤
$Q_{gc}$	Gate - Collector Charge (turn-on)	—	—	43		$V_{\text{GE}} = 15\text{V}$
$t_{d(\text{on})}$	Turn-On Delay Time	—	—	68	ns	$I_C = 25\text{A}, V_{\text{CC}} = 400\text{V}$
$t_r$	Rise Time	—	—	26		$V_{\text{GE}} = 15\text{V}, R_G = 2.35\Omega$ ⑤
$t_{d(\text{off})}$	Turn-Off Delay Time	—	—	480		Energy losses include "tail"
$t_f$	Fall Time	—	—	330		See Fig. 9, 10, 14
$E_{\text{on}}$	Turn-On Switching Loss	—	1.4	—	mJ	
$E_{\text{off}}$	Turn-off Switching Loss	—	4.5	—		
$E_{ts}$	Total Switching Loss	—	5.9	8.2		
$t_{d(\text{on})}$	Turn-On Delay Time	—	33	—	ns	$T_J = 125^\circ\text{C}$
$t_r$	Rise Time	—	15	—		$I_C = 25\text{A}, V_{\text{CC}} = 400\text{V}$
$t_{d(\text{off})}$	Turn-Off Delay Time	—	590	—		$V_{\text{GE}} = 15\text{V}, R_G = 2.35\Omega$ ⑤
$t_f$	Fall Time	—	500	—		Energy losses include "tail"
$E_{ts}$	Total Switching Loss	—	13	—	mJ	See Fig. 11, 14
$L_{\text{C+L}_E}$	Total Inductance	—	6.8	—	nH	Measured from Collector lead (6mm/0.25in. from package) to Emitter lead (6mm / 0.25in. from package)
$C_{\text{ies}}$	Input Capacitance	—	2400	—	pF	$V_{\text{GE}} = 0\text{V}$
$C_{\text{oes}}$	Output Capacitance	—	140	—		$V_{\text{CC}} = 30\text{V}$ See Fig. 7
$C_{\text{res}}$	Reverse Transfer Capacitance	—	28	—		$f = 1.0\text{MHz}$

Note: Corresponding Spice and Saber models are available on the Website.

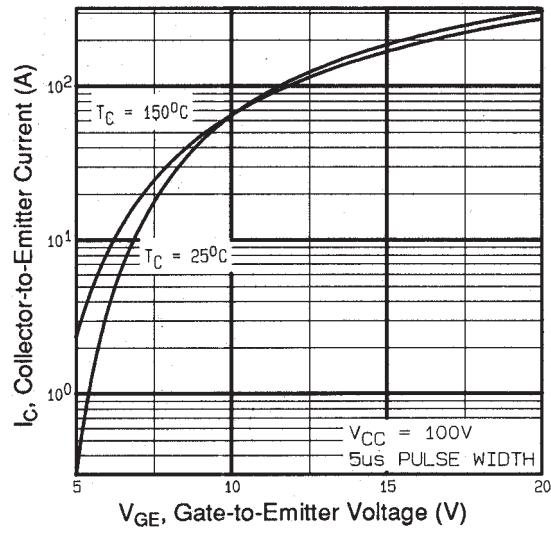
For footnotes refer to the last page



**Fig. 1** - Typical Load Current vs. Frequency  
 (For square wave,  $I=I_{\text{RMS}}$  of fundamental; for triangular wave,  $I=I_{\text{PK}}$ )



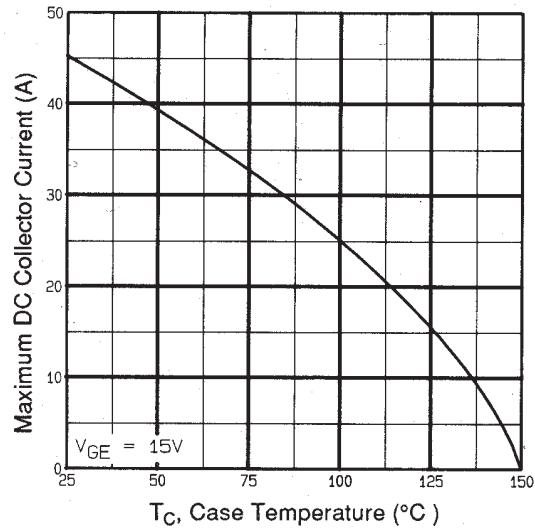
**Fig. 2** - Typical Output Characteristics



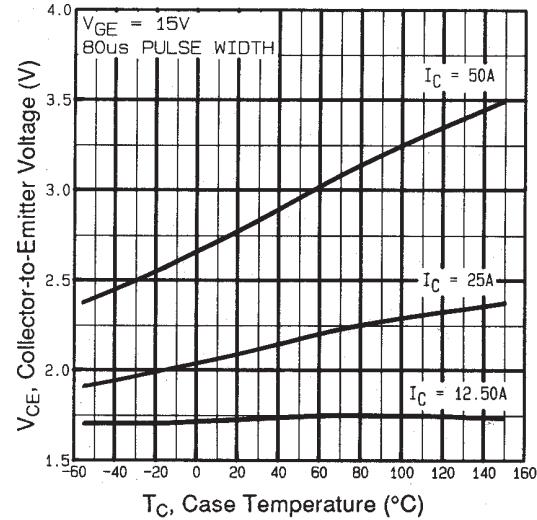
**Fig. 3** - Typical Transfer Characteristics

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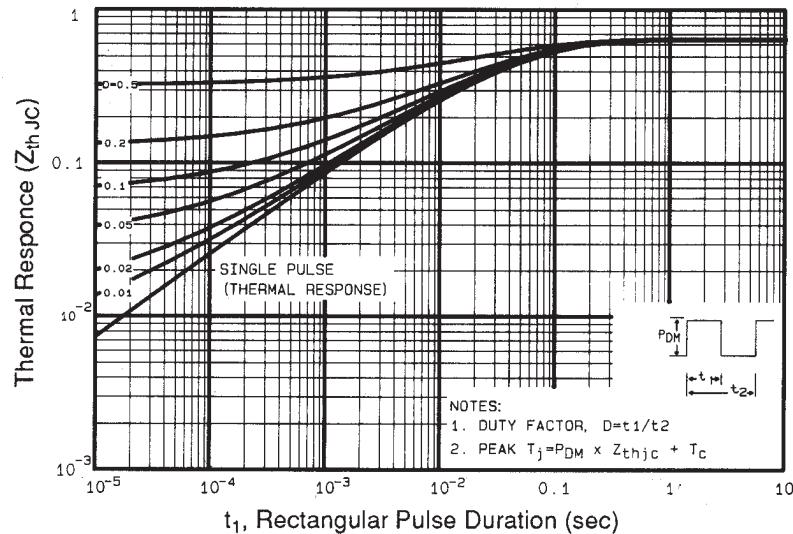
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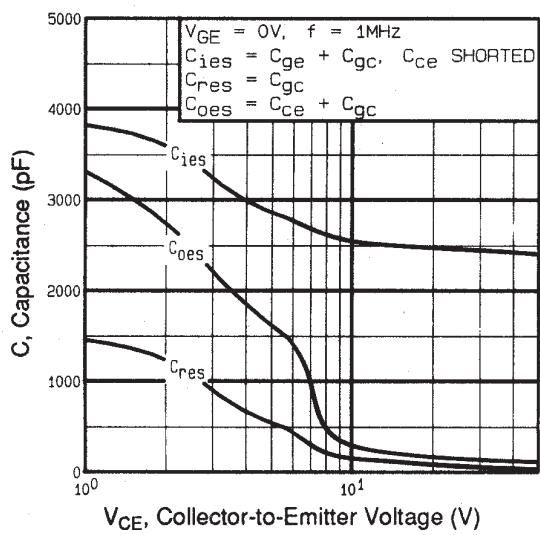
**Fig. 4 - Maximum Collector Current vs. Case Temperature**



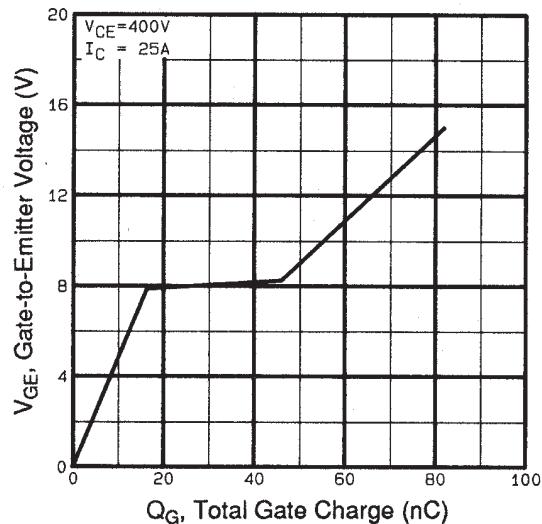
**Fig. 5 - Collector-to-Emitter Voltage vs. Junction Temperature**



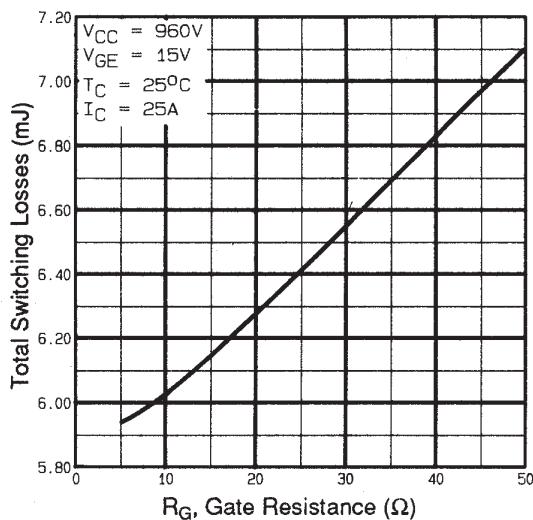
**Fig. 6 - Maximum Effective Transient Thermal Impedance, Junction-to-Case**



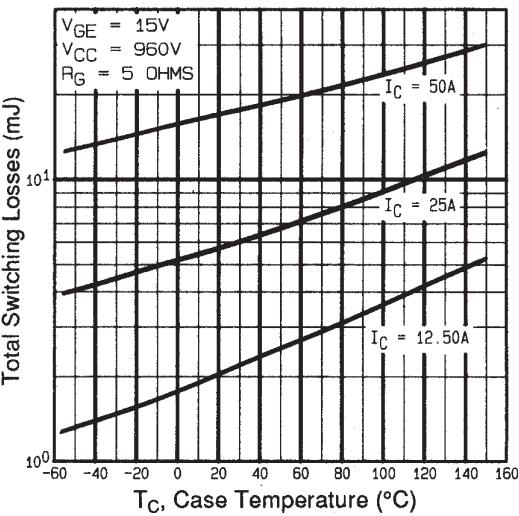
**Fig. 7 - Typical Capacitance vs.  
Collector-to-Emitter Voltage**



**Fig. 8 - Typical Gate Charge vs.  
Gate-to-Emitter Voltage**



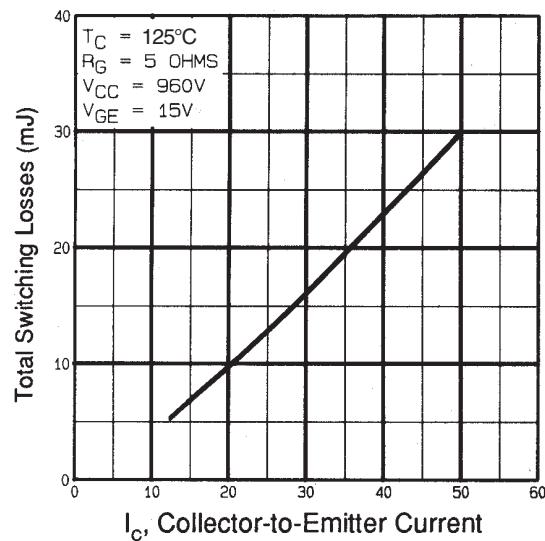
**Fig. 9 - Typical Switching Losses vs. Gate  
Resistance**



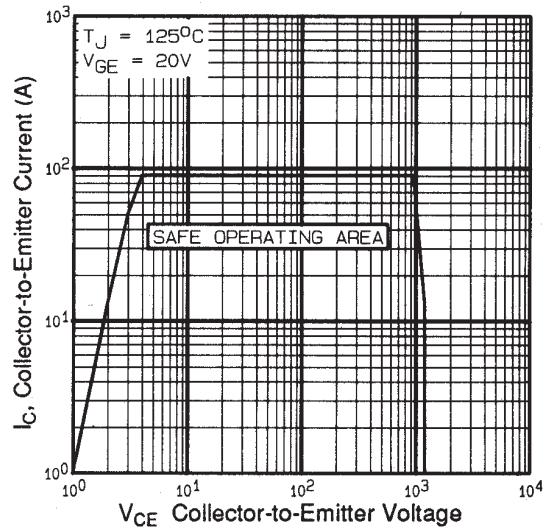
**Fig. 10 - Typical Switching Losses vs.  
Junction Temperature**

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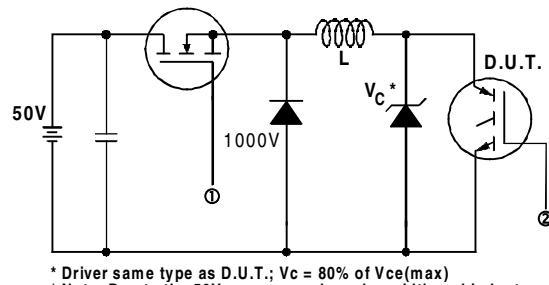
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**Fig. 11** - Typical Switching Losses vs.  
Collector-to-Emitter Current

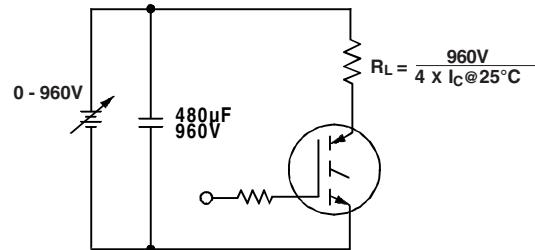


**Fig. 12** - Turn-Off SOA

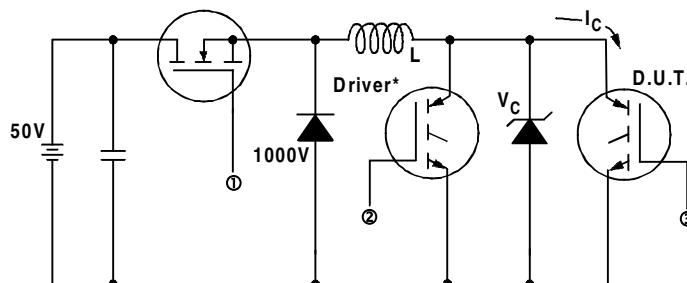


\* Driver same type as D.U.T.; V<sub>c</sub> = 80% of V<sub>ce(max)</sub>  
\* Note: Due to the 50V power supply, pulse width and inductor will increase to obtain rated Id.

**Fig. 13a** - Clamped Inductive Load Test Circuit

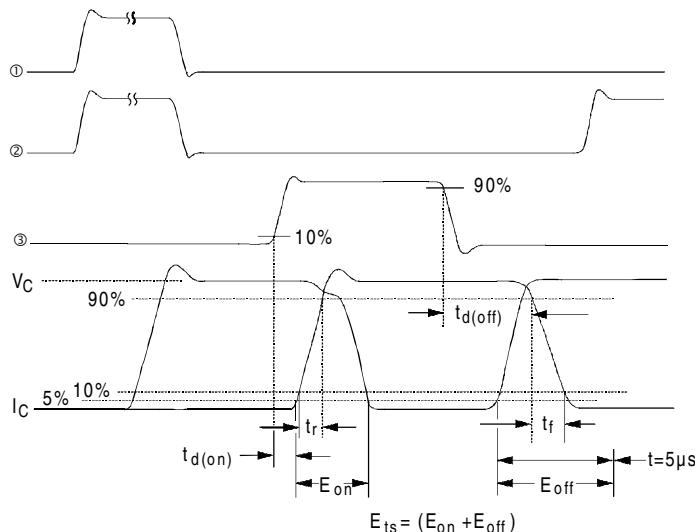


**Fig. 13b** - Pulsed Collector Current Test Circuit



**Fig. 14a** - Switching Loss Test Circuit

\* Driver same type as D.U.T., V<sub>C</sub> = 960V



**Fig. 14b** - Switching Loss Waveforms

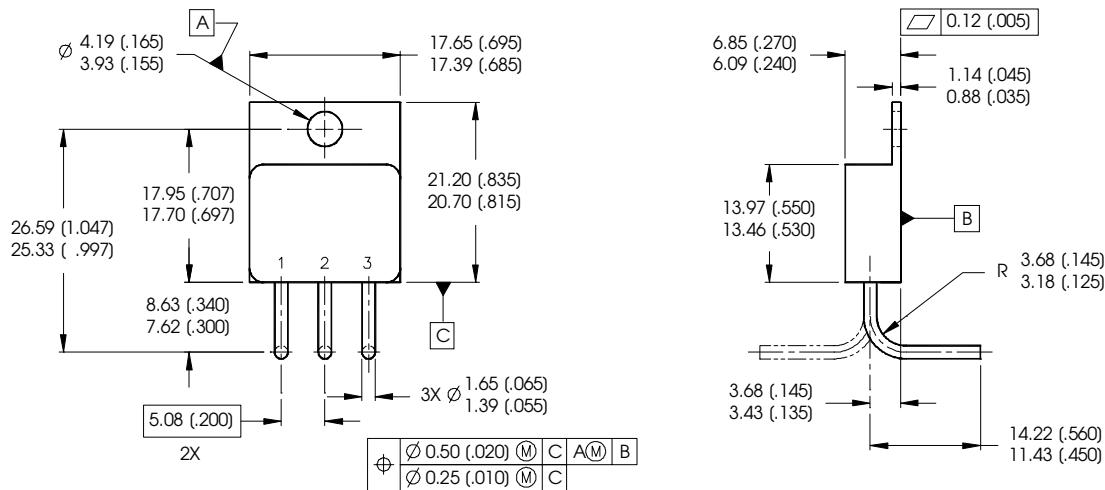
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## Notes:

- ① Repetitive rating;  $V_{GE} = 20V$ , pulse width limited by max. junction temperature.
- ②  $V_{CC} = 80\% (V_{CES})$ ,  $V_{GE} = 20V$ ,  $L = 10\mu H$ ,  $R_G = 5.0\Omega$
- ③ Pulse width  $\leq 80\mu s$ ; duty factor  $\leq 0.1\%$ .
- ④ Pulse width  $5.0\mu s$ , single shot.
- ⑤ Equipment limitation.

## Case Outline and Dimensions — TO-258AA



### NOTES:

1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
3. CONTROLLING DIMENSION: INCH.
4. CONFORMS TO JEDEC OUTLINE TO-258AA BEFORE LEADFORMING.

### LEGEND

- 1 = COLLECTOR
- 2 = Emitter
- 3 = GATE

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